

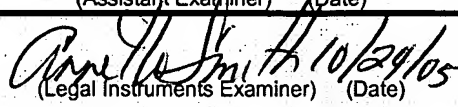


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/759,339	BECKER ET AL.	
	Examiner	Art Unit	
	Hiep Nguyen	2816	

ISSUE CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)					
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
327		374		327	375	376	377		
INTERNATIONAL CLASSIFICATION									
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HIEP NGUYEN 10.18.05 (Assistant Examiner) (Date)		 TUAN T. LAM PRIMARY EXAMINER (Primary Examiner)	Total Claims Allowed: 2	
 (Legal Instruments Examiner) (Date)			O.G. Print Claim(s) 1	O.G. Print Fig. 4A

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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